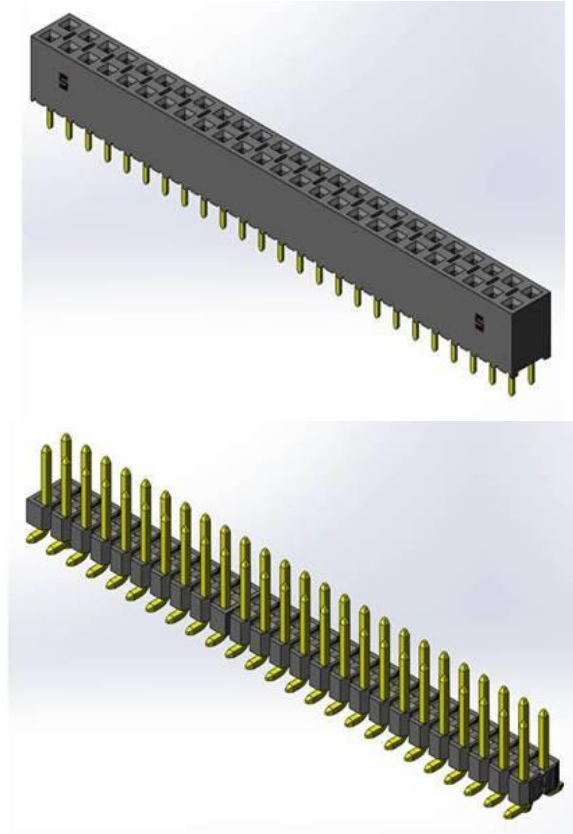




Project Number: Design Qualification Test Report	Tracking Code: 2397636_Report_Rev_1
Requested by: Mark Shireman	Date: 5/27/2022
Part #: BCS-125-F-D-TE/TSM-125-01-F-DV-A	Tech: Peter Chen
Part description: BCS/TSM	Qty to test: 60
Test Start: 07/05/2020	Test Completed: 08/10/2020



## DESIGN QUALIFICATION TEST REPORT

BCS/TSM  
BCS-125-F-D-TE/TSM-125-01-F-DV-A

Tracking Code:2397636_Report_Rev_1	Part #: BCS-125-F-D-TE/TSM-125-01-F-DV-A
Part description: BCS/TSM	

**REVISION HISTORY**

DATA	REV.NUM.	DESCRIPTION	ENG
4/26/2022	1	Initial Issue	PC

## CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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## SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

## APPLICABLE DOCUMENTS

Standards: EIA Publication 364

## TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead free
- 9) Samtec Test PCBs used: PCB-110915-TST, PCB-110917-TST.

## FLOWCHARTS

### Gas Tight

#### Group 1

BCS-125-F-D-TE  
TSM-125-01-F-DV-A  
8 Assemblies

Step	Description
------	-------------

- |    |                                 |
|----|---------------------------------|
| 1. | LLCR (2)                        |
| 2. | Gas Tight (1)                   |
| 3. | LLCR (2)<br>Max Delta = 15 mOhm |

---

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23  
Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

### Normal Force

#### Group 1

BCS-125-F-D-TE  
TSM-125-01-F-DV-A  
8 Contacts Minimum  
Signal Without Thermals

Step	Description
------	-------------

- |    |   |
|----|---|
| 1. | Contact Gaps  |
| 2. | Normal Force (1)<br>Expected Force at Max Deflection = 50 g<br>Deflection = 0.005 " |

#### Group 2

BCS-125-F-D-TE  
TSM-125-01-F-DV-A  
8 Contacts Minimum  
Signal With Thermals

Step	Description
------	-------------

- |    |   |
|----|---|
| 1. | Contact Gaps  |
| 2. | Thermal Age (2)   |
| 3. | Contact Gaps  |
| 4. | Normal Force (1)<br>Expected Force at Max Deflection = 50 g<br>Deflection = 0.005 " |

---

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17  
Test Condition = 4 (105°C)  
Time Condition = B (250 Hours)

**FLOWCHARTS Continued****Thermal Aging**Group 1

BCS-125-F-D-TE

TSM-125-01-F-DV-A

8 Assemblies

**Step Description**

1. Contact Gaps
2. Mating/Unmating Force <sup>(2)</sup>
3. LLCR <sup>(1)</sup>
4. Thermal Age <sup>(3)</sup>
5. LLCR <sup>(1)</sup>  
Max Delta = 15 mOhm
6. Mating/Unmating Force <sup>(2)</sup>
7. Contact Gaps

---

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

**FLOWCHARTS Continued****Mating/Unmating/Durability**

<u>Group 1</u> BCS-125-F-D-TE TSM-125-01-F-DV-A 8 Assemblies		<u>Group 2</u> BCS-150-F-D-TE TSM-150-01-F-DV-A 8 Assemblies		<u>Group 3</u> BCS-105-F-D-TE TSM-105-01-F-DV-A 8 Assemblies		<u>Group 4</u> BCS-125-L-D-TE TSM-125-01-L-DV-A 8 Assemblies	
Step	Description	Step	Description	Step	Description	Step	Description
1.	Contact Gaps	1.	Contact Gaps	1.	Contact Gaps	1.	Contact Gaps
2.	LLCR (2)	2.	Mating/Unmating Force (3)	2.	Mating/Unmating Force (3)	2.	LLCR (2)
3.	Mating/Unmating Force (3)	3.	Cycles Quantity = 25 Cycles	3.	Cycles Quantity = 25 Cycles	3.	Mating/Unmating Force (3)
4.	Cycles Quantity = 25 Cycles	4.	Mating/Unmating Force (3)	4.	Mating/Unmating Force (3)	4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force (3)	5.	Cycles Quantity = 25 Cycles	5.	Cycles Quantity = 25 Cycles	5.	Mating/Unmating Force (3)
6.	Cycles Quantity = 25 Cycles	6.	Mating/Unmating Force (3)	6.	Mating/Unmating Force (3)	6.	Cycles Quantity = 25 Cycles
7.	Mating/Unmating Force (3)	7.	Cycles Quantity = 25 Cycles	7.	Cycles Quantity = 25 Cycles	7.	Mating/Unmating Force (3)
8.	Cycles Quantity = 25 Cycles	8.	Mating/Unmating Force (3)	8.	Mating/Unmating Force (3)	8.	Cycles Quantity = 25 Cycles
9.	Mating/Unmating Force (3)	9.	Cycles Quantity = 25 Cycles	9.	Cycles Quantity = 25 Cycles	9.	Mating/Unmating Force (3)
10.	Cycles Quantity = 25 Cycles	10.	Mating/Unmating Force (3)	10.	Mating/Unmating Force (3)	10.	Cycles Quantity = 25 Cycles
11.	Mating/Unmating Force (3)					11.	Mating/Unmating Force (3)
12.	Contact Gaps					12.	Contact Gaps
13.	LLCR (2) Max Delta = 15 mOhm					13.	LLCR (2) Max Delta = 15 mOhm
14.	Thermal Shock (4)					14.	Thermal Shock (4)
15.	LLCR (2) Max Delta = 15 mOhm					15.	LLCR (2) Max Delta = 15 mOhm
16.	Humidity (1)					16.	Humidity (1)
17.	LLCR (2) Max Delta = 15 mOhm					17.	LLCR (2) Max Delta = 15 mOhm
18.	Mating/Unmating Force (3)					18.	Mating/Unmating Force (3)

**(1) Humidity = EIA-364-31**

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

**(2) LLCR = EIA-364-23**

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

**(3) Mating/Unmating Force = EIA-364-13****(4) Thermal Shock = EIA-364-32**

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

## FLOWCHARTS Continued

**IR/DWV****Pin-to-Pin**

<u>Group 1</u> BCS-125-F-D-TE TSM-125-01-F-DV-A 2 Assemblies		<u>Group 2</u> BCS-125-F-D-TE  2 Assemblies		<u>Group 3</u>  TSM-125-01-F-DV-A 2 Assemblies		<u>Group 4</u> BCS-125-F-D-TE TSM-125-01-F-DV-A 2 Assemblies	
Step	Description	Step	Description	Step	Description	Step	Description
1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	IR <sup>(4)</sup>
						2.	DWV at Test Voltage <sup>(1)</sup>
						3.	Thermal Shock <sup>(5)</sup>
						4.	IR <sup>(4)</sup>
						5.	DWV at Test Voltage <sup>(1)</sup>
						6.	Humidity <sup>(3)</sup>
						7.	IR <sup>(4)</sup>
						8.	DWV at Test Voltage <sup>(1)</sup>

**Row-to-Row**

<u>Group 5</u> BCS-125-F-D-TE TSM-125-01-F-DV-A 2 Assemblies		<u>Group 6</u> BCS-125-F-D-TE  2 Assemblies		<u>Group 7</u>  TSM-125-01-F-DV-A 2 Assemblies		<u>Group 8</u> BCS-125-F-D-TE TSM-125-01-F-DV-A 2 Assemblies	
Step	Description	Step	Description	Step	Description	Step	Description
1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	IR <sup>(4)</sup>
						2.	DWV at Test Voltage <sup>(1)</sup>
						3.	Thermal Shock <sup>(5)</sup>
						4.	IR <sup>(4)</sup>
						5.	DWV at Test Voltage <sup>(1)</sup>
						6.	Humidity <sup>(3)</sup>
						7.	IR <sup>(4)</sup>
						8.	DWV at Test Voltage <sup>(1)</sup>

- (1) DWV at Test Voltage = EIA-364-20  
Test Condition = 1 (Sea Level)  
DWV test voltage is equal to 75% of the lowest breakdown voltage  
Test voltage applied for 60 seconds
- (2) DWV Breakdown = EIA-364-20  
Test Condition = 1 (Sea Level)  
DWV test voltage is equal to 75% of the lowest breakdown voltage  
Test voltage applied for 60 seconds
- (3) Humidity = EIA-364-31  
Test Condition = B (240 Hours)  
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)  
Test Exceptions: ambient pre-condition and delete steps 7a and 7b
- (4) IR = EIA-364-21  
Test Condition = 500 Vdc, 2 Minutes Max
- (5) Thermal Shock = EIA-364-32  
Exposure Time at Temperature Extremes = 1/2 Hour  
Method A, Test Condition = I (-55°C to +85°C)  
Test Duration = A-3 (100 Cycles)

**FLOWCHARTS Continued****Current Carrying Capacity**Group 1

BCS-150-F-D-TE  
TSM-150-01-F-DV-A  
2 Pins Powered  
Signal

**Step Description**

1. CCC <sup>(1)</sup>  
Rows = 2  
Number of Positions = 1

Group 2

BCS-150-F-D-TE  
TSM-150-01-F-DV-A  
4 Pins Powered  
Signal

**Step Description**

1. CCC <sup>(1)</sup>  
Rows = 2  
Number of Positions = 2

Group 3

BCS-150-F-D-TE  
TSM-150-01-F-DV-A  
6 Pins Powered  
Signal

**Step Description**

1. CCC <sup>(1)</sup>  
Rows = 2  
Number of Positions = 3

Group 4

BCS-150-F-D-TE  
TSM-150-01-F-DV-A  
8 Pins Powered  
Signal

**Step Description**

1. CCC <sup>(1)</sup>  
Rows = 2  
Number of Positions = 4

Group 5

BCS-150-F-D-TE  
TSM-150-01-F-DV-A  
100 Pins Powered  
Signal

**Step Description**

1. CCC <sup>(1)</sup>  
Rows = 2  
Number of Positions = 50

(1) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT,65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT,85°C, 95°C and 115°C after derating 20% and based on 125°C



**FLOWCHARTS Continued****Mechanical Shock/Random Vibration/LLCR**Group 1

BCS-125-F-D-TE

TSM-125-01-F-DV-A

8 Assemblies

**Step Description**

1. LLCR <sup>(1)</sup>
2. Mechanical Shock <sup>(2)</sup>
3. Random Vibration <sup>(3)</sup>
4. LLCR <sup>(1)</sup>  
Max Delta = 15 mOhm

---

**(1) LLCR = EIA-364-23**

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

**(2) Mechanical Shock = EIA-364-27**

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

**(3) Random Vibration = EIA-364-28**

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

**Mechanical Shock/Random Vibration/Event Detection**Group 1

BCS-125-F-D-TE

TSM-125-01-F-DV-A

60 Points

**Step Description**

1. Nanosecond Event Detection  
(Mechanical Shock) <sup>(1)</sup>
2. Nanosecond Event Detection  
(Random Vibration) <sup>(2)</sup>

---

**(1) Nanosecond Event Detection (Mechanical Shock)**

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-27 for Mechanical Shock:

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

**(2) Nanosecond Event Detection (Random Vibration)**

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-28 for Random Vibration:

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

**ATTRIBUTE DEFINITIONS**

The following is a brief, simplified description of attributes.

**THERMAL SHOCK:**

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

**THERMAL:**

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition 4 at 105° C
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

**HUMIDITY:**

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

**MECHANICAL SHOCK (Specified Pulse):**

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

**VIBRATION:**

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G<sup>2</sup> / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

**NANOSECOND-EVENT DETECTION:**

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes.

**MATING/UNMATING:**

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

**LLCR:**

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0$  mOhms: -----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: -----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: -----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms: -----Unstable
  - f.  $>+1000$  mOhms:-----Open Failure

**GAS TIGHT:**

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0$  mOhms: -----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: -----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: -----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms: -----Unstable
  - f.  $>+1000$  mOhms:-----Open Failure
- 4) Procedure:
  - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
  - b. Test Conditions:
    - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
    - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
    - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
    - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
    - v. Exposure time, 55 to 65 minutes.
    - vi. The samples shall be no closer to the chamber walls than 1 inch and no closer to the surface of the acid than 3 inches.
    - vii. The samples shall be dried after exposure for a minimum of 1 hour.
    - viii. Drying temperature 50° C
    - ix. The final LLCR shall be conducted within 1 hour after drying.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes.

**TEMPERATURE RISE (Current Carrying Capacity, CCC):**

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of  $I^2R$  (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
  - a. Self-heating (resistive)
  - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at four temperature points are reported:
  - a. Ambient
  - b. 85° C
  - c. 95° C
  - d. 115° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat buildup) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

**NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):**

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the loose state, *not* inserted in connector housing.
- 3) The contacts shall be prepared to allow access to the spring member at the same attitude and deflection level as would occur in actual use.
- 4) In the event that portions of the contact prevent insertion of the test probe and/or deflection of the spring member under evaluation, said material shall be removed leaving the appropriate contact surfaces exposed.
- 5) In the case of multi-tine contacts, each tine shall be tested independently on separate samples as required.
- 6) The connector housing shall be simulated, if required, in order to provide an accurate representation of the actual contact system performance.
- 7) A holding fixture shall be fashioned to allow the contact to be properly deflected.
- 8) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC<sup>2</sup>, computer controlled test stand with a deflection measurement system accuracy of 5 µm (0.0002").
- 9) The probe shall be attached to a Dillon P/N 49761-0105, 5 N (1.1 Lb) load cell providing an accuracy of ± 0.2%.
- 10) The nominal deflection rate shall be 5 mm (0.2")/minute.
- 11) Unless otherwise noted a minimum of five contacts shall be tested.
- 12) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 13) The system shall utilize the TC<sup>2</sup> software in order to acquire and record the test data.
- 14) The permanent set of each contact shall be measured within the TC<sup>2</sup> software.
- 15) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes

**INSULATION RESISTANCE (IR):**

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

**1) PROCEDURE:**

- a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
- b. Test Conditions:
  - i. Between Adjacent Contacts or Signal-to-Ground
  - ii. Electrification Time 2.0 minutes
  - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.

**2) MEASUREMENTS:**

- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

**1) PROCEDURE:**

- a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
- b. Test Conditions:
  - i. Between Adjacent Contacts or Signal-to-Ground
  - ii. Barometric Test Condition 1
  - iii. Rate of Application 500 V/Sec
  - iv. Test Voltage (VAC) until breakdown occurs

**2) MEASUREMENTS/CALCULATIONS**

- a. The breakdown voltage shall be measured and recorded.
- b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
- c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

## RESULTS

### Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise-----5.0 A per contact with 2 contacts (2x1) powered
- CCC for a 30°C Temperature Rise-----4.1 A per contact with 4 contacts (2x2) powered
- CCC for a 30°C Temperature Rise-----3.5 A per contact with 6 contacts (2x3) powered
- CCC for a 30°C Temperature Rise-----3.3 A per contact with 8 contacts (2x4) powered
- CCC for a 30°C Temperature Rise-----2.0 A per contact with 164 contacts (2x82) powered

### Mating – Unmating Forces

#### Thermal Aging Group (BCS-125-F-D-TE/TSM-125-01-F-DV-A)

- Initial
  - Mating
    - Min ----- 9.68 Lbs
    - Max-----10.85 Lbs
  - Unmating
    - Min ----- 8.52 Lbs
    - Max----- 9.15 Lbs
- After Thermal
  - Mating
    - Min -----11.35 Lbs
    - Max-----12.86 Lbs
  - Unmating
    - Min -----10.55 Lbs
    - Max-----11.07 Lbs

**RESULTS Continued****Mating – Unmating Forces****Mating-Unmating Durability Group (BCS-125-F-D-TE/TSM-125-01-F-DV-A)**

- **Initial**
  - **Mating**
    - **Min** ----- 8.53 Lbs
    - **Max** ----- 12.99 Lbs
  - **Unmating**
    - **Min** ----- 7.64 Lbs
    - **Max** ----- 9.27 Lbs
- **After 25 Cycles**
  - **Mating**
    - **Min** ----- 11.77 Lbs
    - **Max** ----- 15.55 Lbs
  - **Unmating**
    - **Min** ----- 10.80 Lbs
    - **Max** ----- 13.82 Lbs
- **After 50 Cycles**
  - **Mating**
    - **Min** ----- 13.31 Lbs
    - **Max** ----- 18.81 Lbs
  - **Unmating**
    - **Min** ----- 12.58 Lbs
    - **Max** ----- 16.14 Lbs
- **After 75 Cycles**
  - **Mating**
    - **Min** ----- 14.78 Lbs
    - **Max** ----- 20.99 Lbs
  - **Unmating**
    - **Min** ----- 13.81 Lbs
    - **Max** ----- 17.80 Lbs
- **After 100 Cycles**
  - **Mating**
    - **Min** ----- 16.51 Lbs
    - **Max** ----- 22.01 Lbs
  - **Unmating**
    - **Min** ----- 15.58 Lbs
    - **Max** ----- 18.66 Lbs
- **Humidity**
  - **Mating**
    - **Min** ----- 9.65 Lbs
    - **Max** ----- 12.52 Lbs
  - **Unmating**
    - **Min** ----- 9.14 Lbs
    - **Max** ----- 11.05 Lbs

**RESULTS Continued****Mating – Unmating Forces****Mating-Unmating Durability Group (BCS-125-L-D-TE/TSM-125-01-L-DV-A)**

- **Initial**
  - **Mating**
    - **Min** -----11.75 Lbs
    - **Max** -----13.14 Lbs
  - **Unmating**
    - **Min** ----- 8.74 Lbs
    - **Max** -----10.29 Lbs
- **After 25 Cycles**
  - **Mating**
    - **Min** -----13.25 Lbs
    - **Max** -----14.70 Lbs
  - **Unmating**
    - **Min** -----10.90 Lbs
    - **Max** -----12.48 Lbs
- **After 50 Cycles**
  - **Mating**
    - **Min** -----14.36 Lbs
    - **Max** -----15.66 Lbs
  - **Unmating**
    - **Min** -----12.32 Lbs
    - **Max** -----13.92 Lbs
- **After 75 Cycles**
  - **Mating**
    - **Min** -----15.27 Lbs
    - **Max** -----16.66 Lbs
  - **Unmating**
    - **Min** -----13.40 Lbs
    - **Max** -----14.78 Lbs
- **After 100 Cycles**
  - **Mating**
    - **Min** -----16.23 Lbs
    - **Max** -----17.58 Lbs
  - **Unmating**
    - **Min** -----14.08 Lbs
    - **Max** -----15.47 Lbs
- **Humidity**
  - **Mating**
    - **Min** -----11.11 Lbs
    - **Max** -----12.93 Lbs
  - **Unmating**
    - **Min** ----- 9.88 Lbs
    - **Max** -----11.16 Lbs



**RESULTS Continued****Mating-Unmating Basic (BCS-150-F-D-TE/TSM-150-01-F-DV-A)**

- **Initial**
  - **Mating**
    - **Min** -----20.87 Lbs
    - **Max** -----26.92 Lbs
  - **Unmating**
    - **Min** -----14.93 Lbs
    - **Max** -----22.69 Lbs
- **After 25 Cycles**
  - **Mating**
    - **Min** -----26.82 Lbs
    - **Max** -----31.08 Lbs
  - **Unmating**
    - **Min** -----24.20 Lbs
    - **Max** -----27.69 Lbs
- **After 50 Cycles**
  - **Mating**
    - **Min** -----30.61 Lbs
    - **Max** -----35.68 Lbs
  - **Unmating**
    - **Min** -----27.59 Lbs
    - **Max** -----31.51 Lbs
- **After 75 Cycles**
  - **Mating**
    - **Min** -----33.24 Lbs
    - **Max** -----40.37 Lbs
  - **Unmating**
    - **Min** -----29.47 Lbs
    - **Max** -----34.38 Lbs
- **After 100 Cycles**
  - **Mating**
    - **Min** -----34.81 Lbs
    - **Max** -----43.00 Lbs
  - **Unmating**
    - **Min** -----30.48 Lbs
    - **Max** -----36.36 Lbs

**RESULTS Continued****Mating-Unmating Basic (BCS-105-F-D-TE/TSM-105-01-F-DV-A)**

- **Initial**
  - **Mating**
    - Min ----- 1.88 Lbs
    - Max----- 2.64 Lbs
  - **Unmating**
    - Min ----- 1.33 Lbs
    - Max----- 2.33 Lbs
- **After 25 Cycles**
  - **Mating**
    - Min ----- 2.10 Lbs
    - Max----- 3.27 Lbs
  - **Unmating**
    - Min ----- 1.81 Lbs
    - Max----- 3.16 Lbs
- **After 50 Cycles**
  - **Mating**
    - Min ----- 2.43 Lbs
    - Max----- 3.65 Lbs
  - **Unmating**
    - Min ----- 1.90 Lbs
    - Max----- 3.52 Lbs
- **After 75 Cycles**
  - **Mating**
    - Min ----- 2.78 Lbs
    - Max----- 4.09 Lbs
  - **Unmating**
    - Min ----- 2.67 Lbs
    - Max----- 3.82 Lbs
- **After 100 Cycles**
  - **Mating**
    - Min ----- 3.09 Lbs
    - Max----- 4.21 Lbs
  - **Unmating**
    - Min ----- 2.95 Lbs
    - Max----- 3.94 Lbs

**Normal Force at 0.0036 inch deflection****Signal Pin:**

- **Initial**
  - Min ----- 149.30 gf      Set ---- 0.0000 in
  - Max ----- 214.20 gf      Set ---- 0.0003 in
- **Thermal**
  - Min ----- 132.30 gf      Set ---- 0.0001 in
  - Max ----- 172.90 gf      Set ---- 0.0007 in

**RESULTS Continued****Insulation Resistance minimums, IR****Pin to Pin**

- **Initial**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed
- **Thermal Shock**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed
- **Humidity**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed

**Row to Row**

- **Initial**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed
- **Thermal Shock**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed
- **Humidity**
  - Mated -----45000 Meg  $\Omega$  ----- Passed
  - Unmated -----45000 Meg  $\Omega$  ----- Passed

**Dielectric Withstanding Voltage minimums, DWV**

- **Minimums**
  - Breakdown Voltage ----- 1997 VAC
  - Test Voltage ----- 1550 VAC
  - Working Voltage ----- 495 VAC

**Pin to Pin**

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

**Row to Row**

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

**RESULTS Continued****LLCR Gas Tight Group (192 LLCR test points)**

- Initial -----5.77 mOhms Max
- Gas-Tight
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure

**LLCR Thermal Aging Group (192 LLCR test points)**

- Initial -----5.43 mOhms Max
- Thermal
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure

**LLCR Mating/Unmating Durability Group (BCS-125-F-D-TE/TSM-125-01-F-DV-A) (192 LLCR test points)**

- Initial -----5.20 mOhms Max
- Durability, 100 Cycles
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure
- Thermal Shock
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure
- Humidity
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure

**RESULTS Continued****LLCR Mating/Unmating Durability Group (BCS-125-L-D-TE/TSM-125-01-L-DV-A) (192 LLCR test points)**

- **Initial** -----5.39 mOhms Max
- **Durability, 100 Cycles**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure
- **Thermal Shock**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure
- **Humidity**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure

**LLCR Shock & Vibration Group (192 LLCR test points)**

- **Initial** -----4.99 mOhms Max
- **Shock & Vibration**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +1000 mOhms -----0 Points ----- Unstable
  - >+1000 mOhms -----0 Points ----- Open Failure

**Mechanical Shock & Random Vibration:**

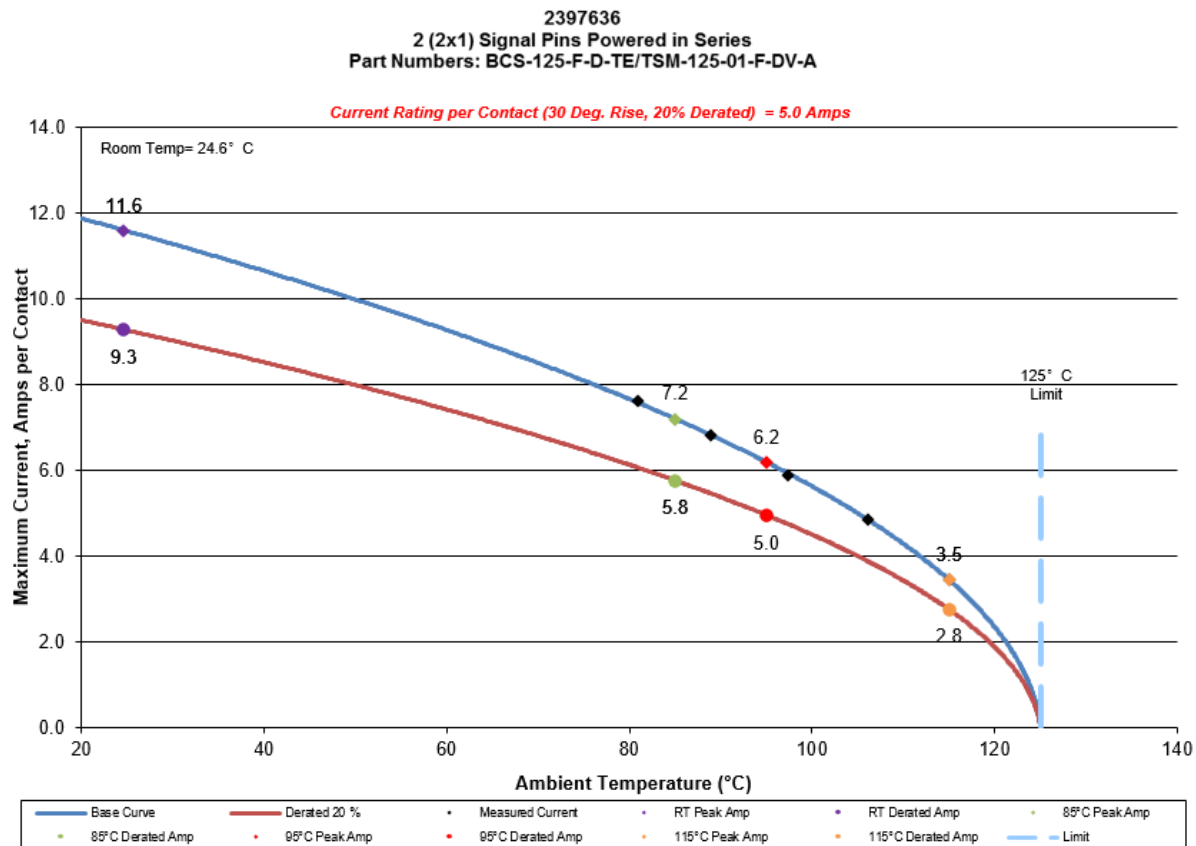
- **Shock**
  - **No Damage**----- Passed
  - **50 Nanoseconds**----- Passed
- **Vibration**
  - **No Damage**----- Passed
  - **50 Nanoseconds**----- Passed

## DATA SUMMARIES

### TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:

- a. Linear configuration with 8 adjacent conductors/contacts powered

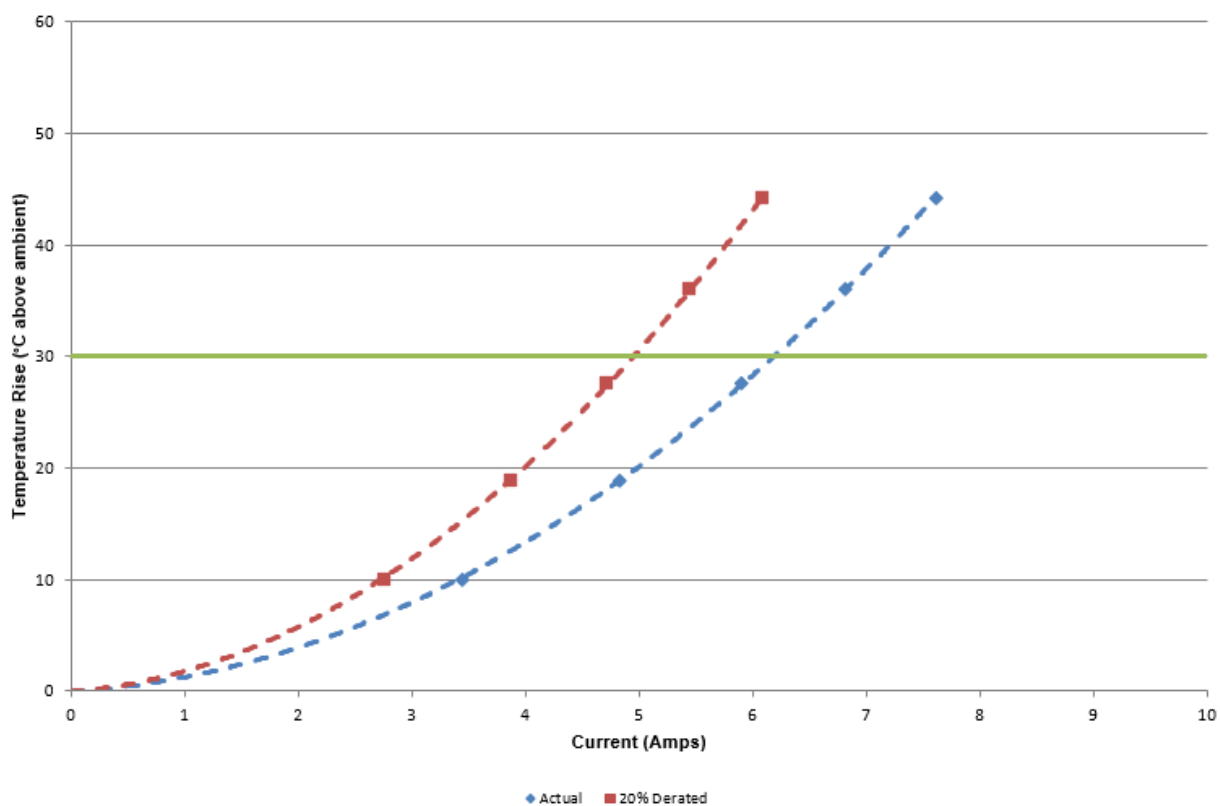


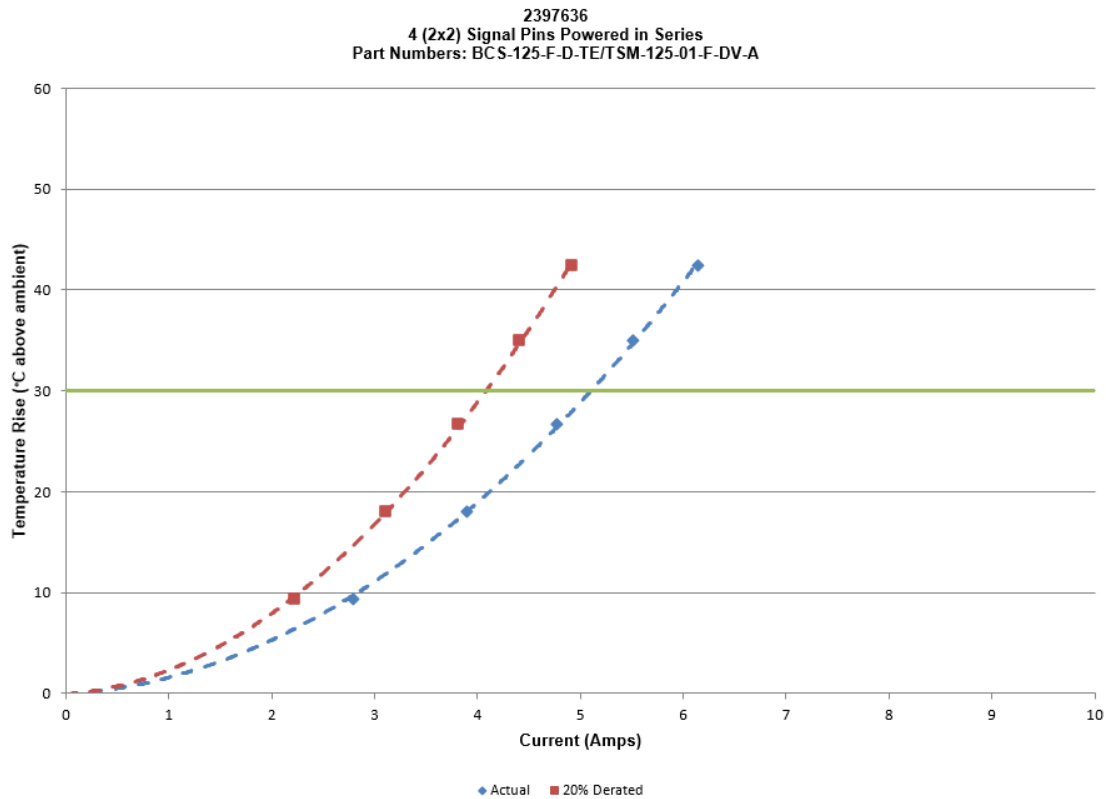
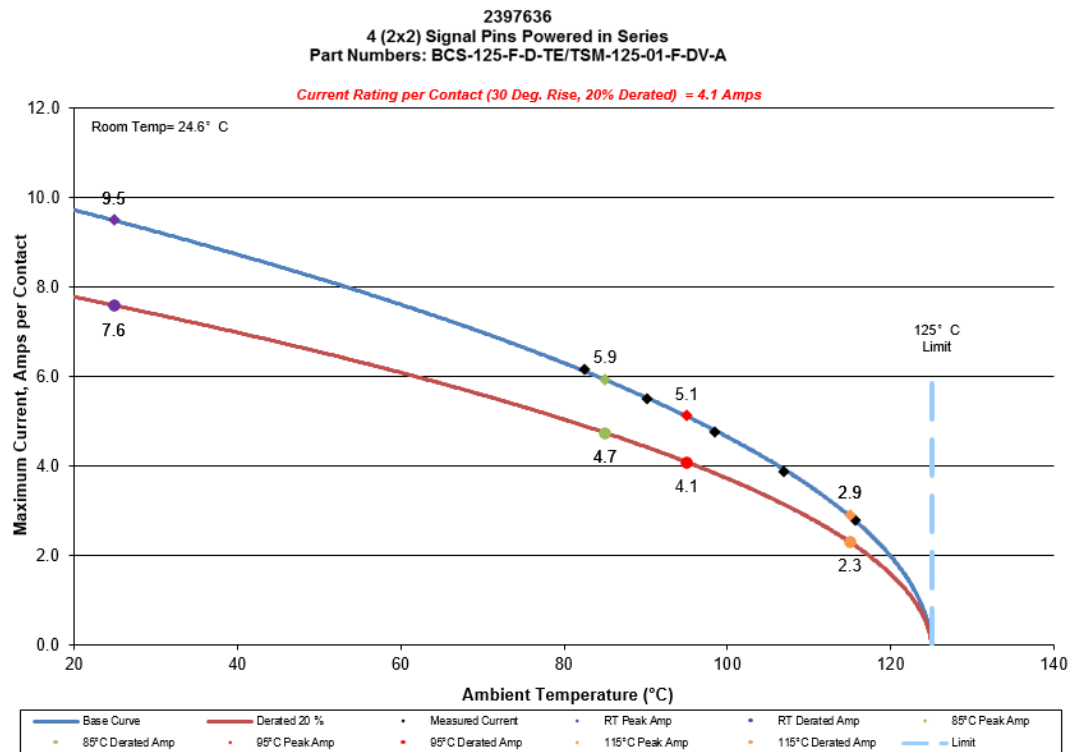
**DATA SUMMARIES Continued**

2397636

2 (2x1) Signal Pins Powered in Series

Part Numbers: BCS-125-F-D-TE/TSM-125-01-F-DV-A

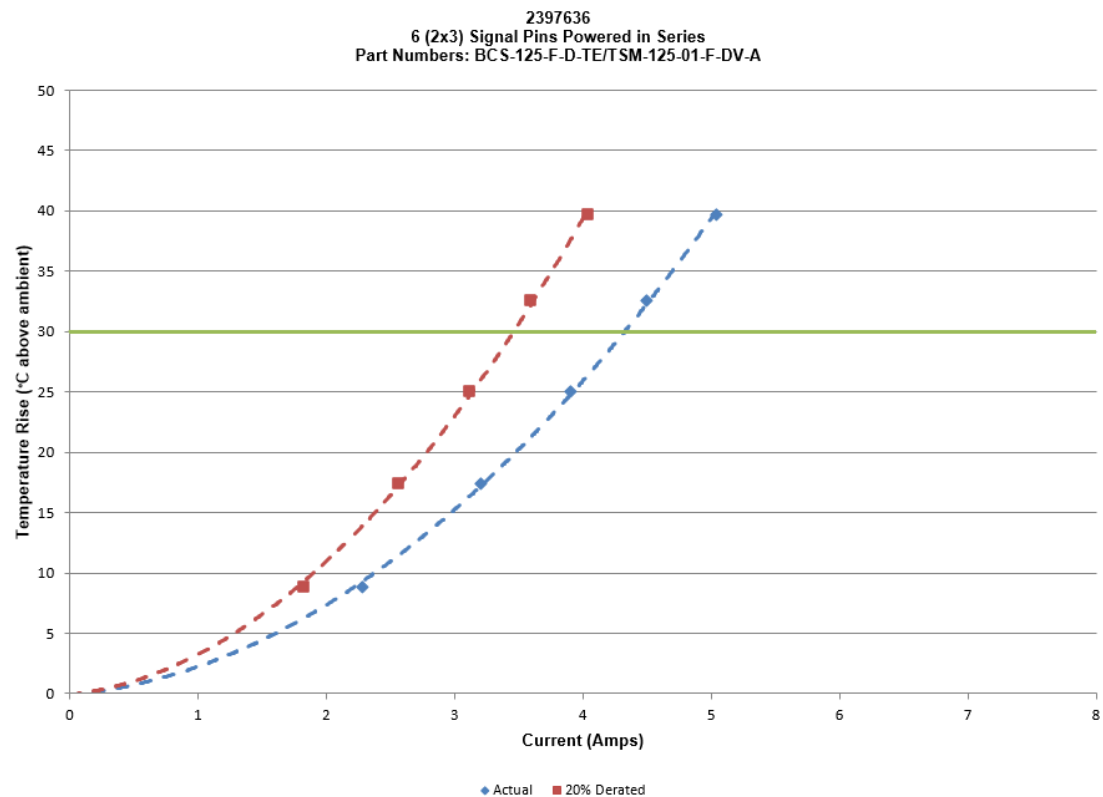
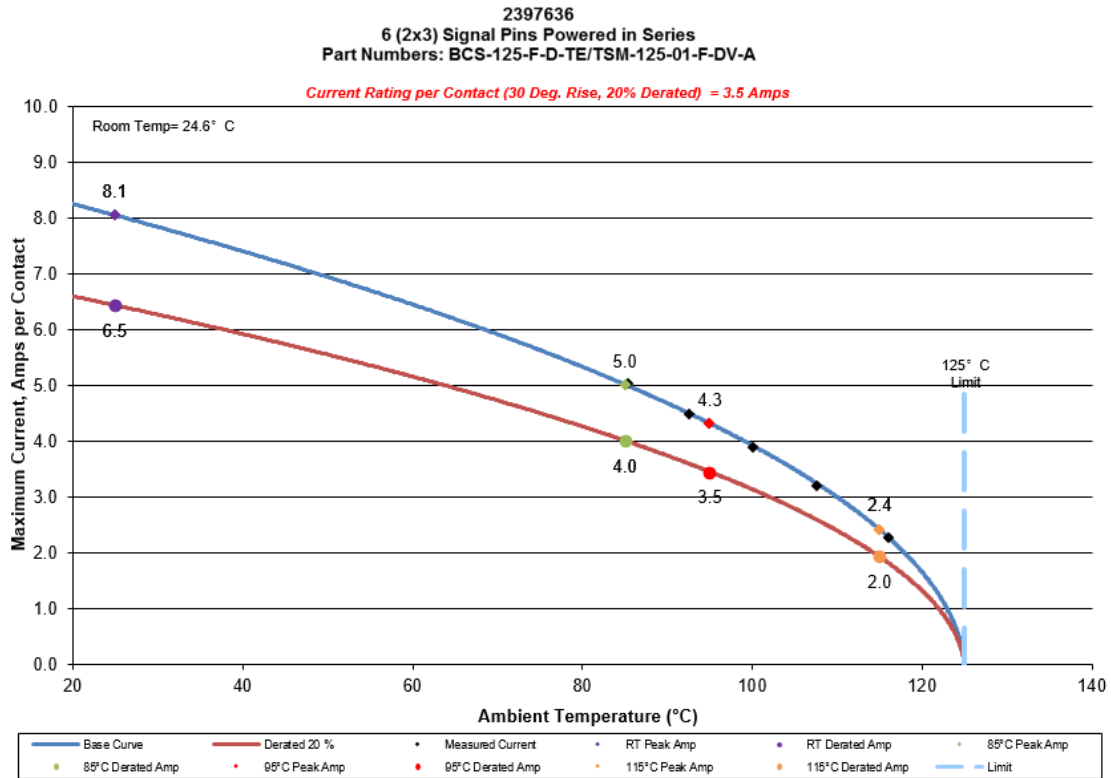


**DATA SUMMARIES Continued****b. Linear configuration with 4 adjacent conductors/contacts powered**



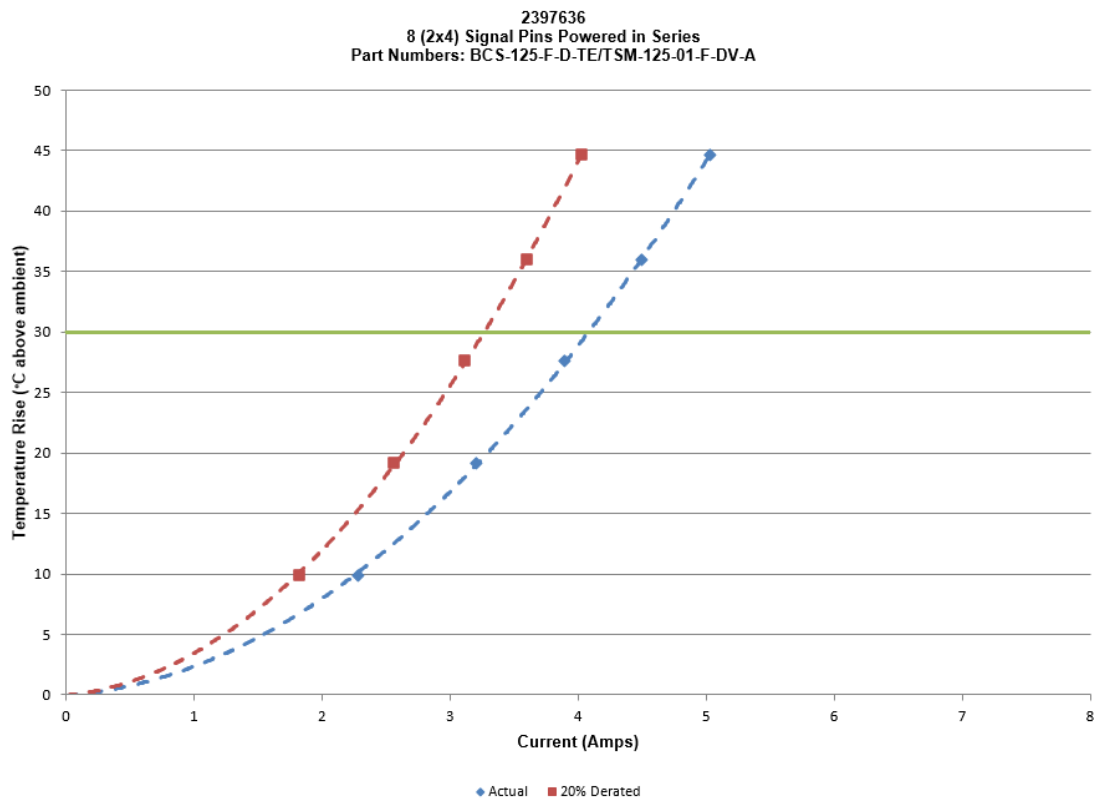
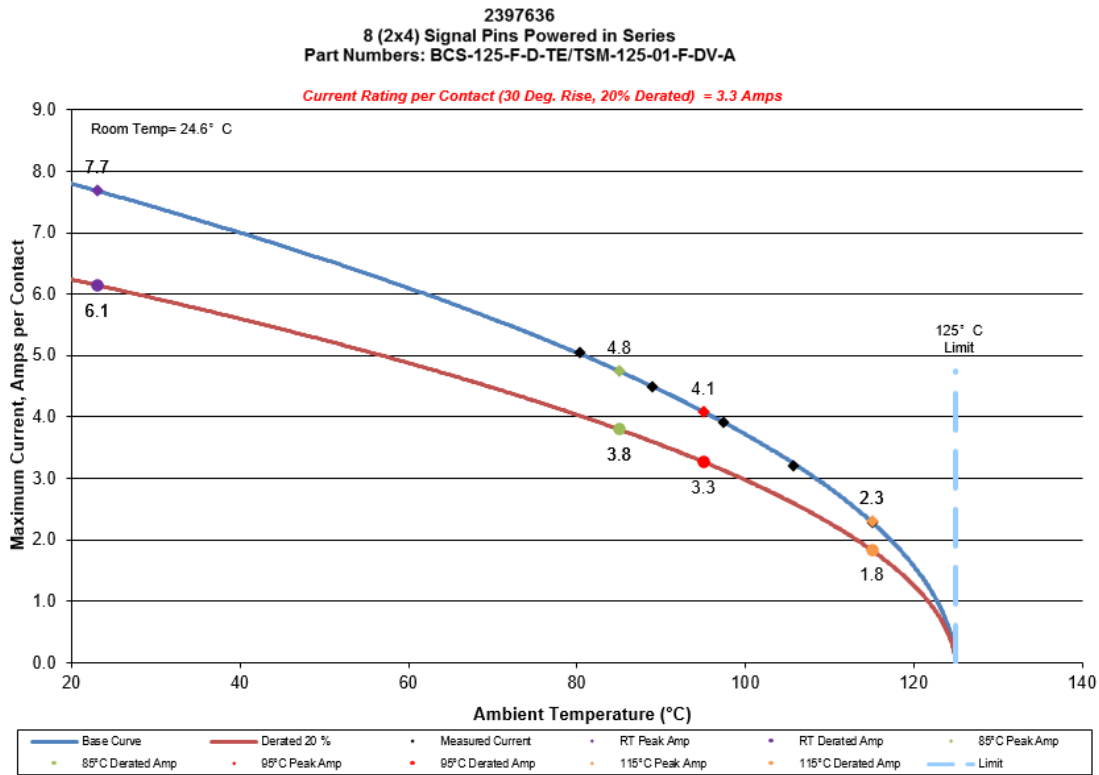
**DATA SUMMARIES Continued**

c. Linear configuration with 6 adjacent conductors/contacts powered



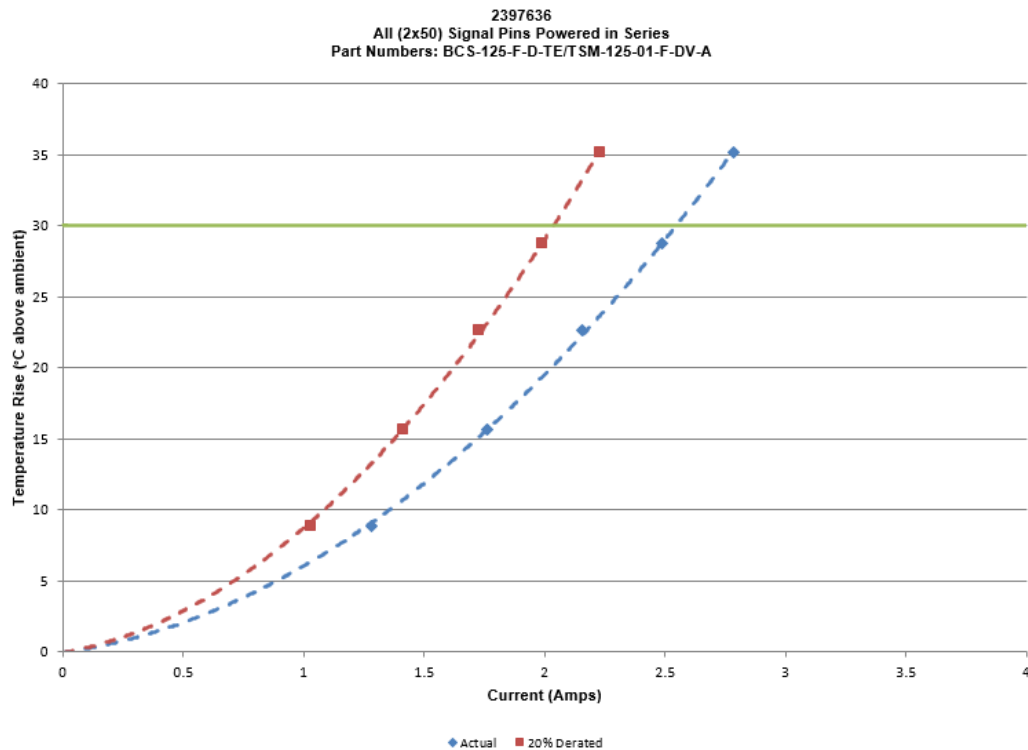
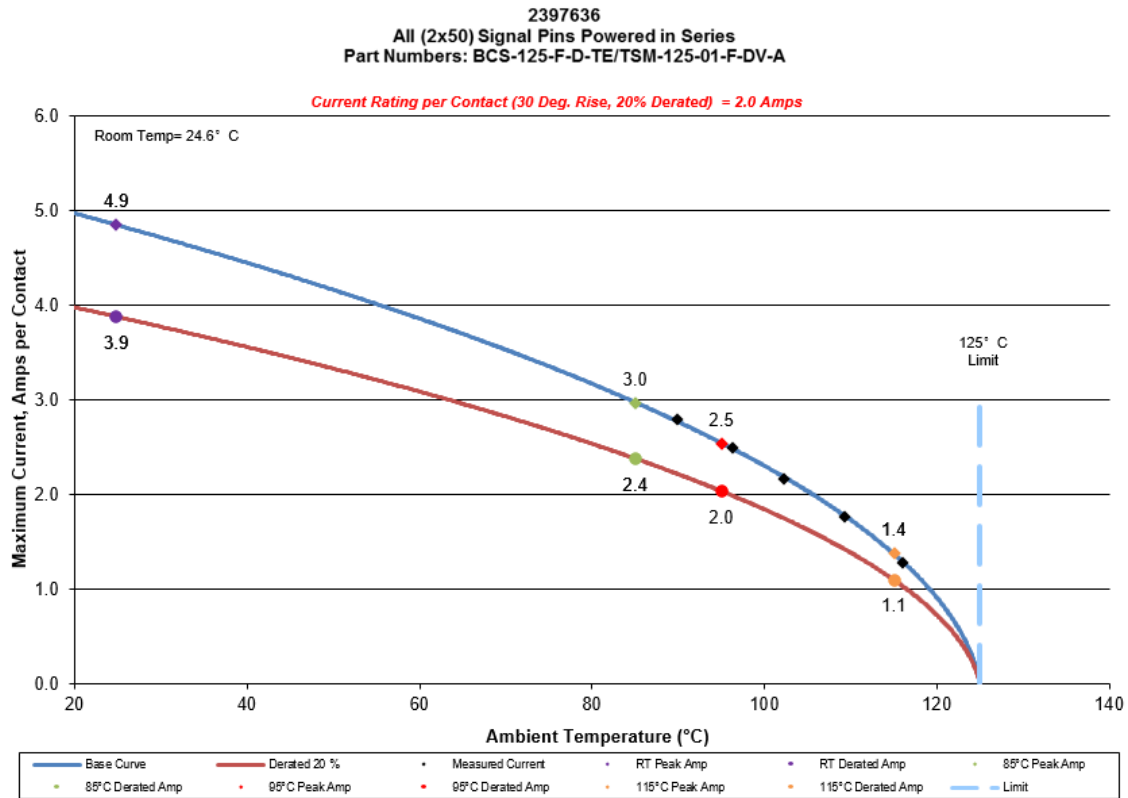
**DATA SUMMARIES Continued**

d. Linear configuration with 8 adjacent conductors/contacts powered



**DATA SUMMARIES Continued**

e. Linear configuration with all adjacent conductors/contacts powered



**DATA SUMMARIES Continued****MATING-UNMATING FORCE:****Thermal Aging Group (BCS-125-F-D-TE/TSM-125-01-F-DV-A)**

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	43.06	9.68	37.90	8.52	50.48	11.35	46.93	10.55
Maximum	48.26	10.85	40.70	9.15	57.20	12.86	49.24	11.07
<b>Average</b>	45.02	<b>10.12</b>	39.18	<b>8.81</b>	53.97	<b>12.13</b>	48.08	<b>10.81</b>
St Dev	1.76	0.39	1.06	0.24	2.43	0.55	0.81	0.18
Count	8	8	8	8	8	8	8	8

**Mating-Unmating Durability Group (BCS-125-F-D-TE/TSM-125-01-F-DV-A)**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	37.94	8.53	33.98	7.64	52.35	11.77	48.04	10.80
Maximum	57.78	12.99	41.23	9.27	69.17	15.55	61.47	13.82
<b>Average</b>	46.16	<b>10.38</b>	38.44	<b>8.64</b>	64.40	<b>14.48</b>	57.85	<b>13.01</b>
St Dev	5.89	1.32	2.77	0.62	5.50	1.24	4.44	1.00
Count	8	8	8	8	8	8	8	8

	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	59.20	13.31	55.96	12.58	65.74	14.78	61.43	13.81
Maximum	83.67	18.81	71.79	16.14	93.36	20.99	79.17	17.80
<b>Average</b>	76.30	<b>17.15</b>	67.87	<b>15.26</b>	84.20	<b>18.93</b>	74.18	<b>16.68</b>
St Dev	7.75	1.74	5.32	1.20	8.32	1.87	5.55	1.25
Count	8	8	8	8	8	8	8	8

	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	73.44	16.51	69.30	15.58	42.92	9.65	40.65	9.14
Maximum	97.90	22.01	83.00	18.66	55.69	12.52	49.15	11.05
<b>Average</b>	88.95	<b>20.00</b>	78.05	<b>17.55</b>	49.89	<b>11.22</b>	44.72	<b>10.05</b>
St Dev	7.72	1.73	4.33	0.97	3.74	0.84	2.72	0.61
Count	8	8	8	8	8	8	8	8

**DATA SUMMARIES Continued****Mating-Unmating Durability Group (BCS-125-L-D-TE/TSM-125-01-L-DV-A)**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	52.26	11.75	38.88	8.74	58.94	13.25	48.48	10.90
Maximum	58.45	13.14	45.77	10.29	65.39	14.70	55.51	12.48
<b>Average</b>	55.34	<b>12.44</b>	42.82	<b>9.63</b>	62.12	<b>13.97</b>	52.22	<b>11.74</b>
St Dev	2.15	0.48	2.32	0.52	2.57	0.58	2.15	0.48
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	63.87	14.36	54.80	12.32	67.92	15.27	59.60	13.40
Maximum	69.66	15.66	61.92	13.92	74.10	16.66	65.74	14.78
<b>Average</b>	67.73	<b>15.23</b>	58.85	<b>13.23</b>	71.63	<b>16.10</b>	62.93	<b>14.15</b>
St Dev	1.93	0.43	2.19	0.49	2.05	0.46	1.92	0.43
Count	8	8	8	8	8	8	8	8
	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	72.19	16.23	62.63	14.08	49.42	11.11	43.96	9.88
Maximum	78.20	17.58	68.81	15.47	57.51	12.93	49.63	11.16
<b>Average</b>	75.53	<b>16.98</b>	66.05	<b>14.85</b>	53.87	<b>12.11</b>	45.90	<b>10.32</b>
St Dev	1.78	0.40	1.90	0.43	2.77	0.62	2.07	0.46
Count	8	8	8	8	8	8	8	8

**DATA SUMMARIES Continued****Mating-Unmating Basic (BCS-150-F-D-TE/TSM-150-01-F-DV-A)**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	92.83	20.87	66.41	14.93	119.30	26.82	107.64	24.20
Maximum	119.74	26.92	100.93	22.69	138.24	31.08	123.17	27.69
<b>Average</b>	102.27	<b>22.99</b>	73.98	<b>16.63</b>	127.30	<b>28.62</b>	113.42	<b>25.50</b>
St Dev	9.59	2.16	11.56	2.60	6.72	1.51	5.18	1.17
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	136.15	30.61	122.72	27.59	147.85	33.24	131.08	29.47
Maximum	158.70	35.68	140.16	31.51	179.57	40.37	152.92	34.38
<b>Average</b>	147.37	<b>33.13</b>	129.76	<b>29.17</b>	162.87	<b>36.62</b>	140.33	<b>31.55</b>
St Dev	8.04	1.81	5.94	1.33	9.54	2.14	6.64	1.49
Count	8	8	8	8	8	8	8	8
	After 100 Cycles							
	Mating		Unmating					
	Newtons	Force (Lbs)	Newtons	Force (Lbs)				
Minimum	154.83	34.81	135.58	30.48				
Maximum	191.26	43.00	161.73	36.36				
<b>Average</b>	173.63	<b>39.04</b>	148.05	<b>33.29</b>				
St Dev	10.84	2.44	7.63	1.72				
Count	8	8	8	8				

**DATA SUMMARIES Continued****Mating-Unmating Basic (BCS-105-F-D-TE/TSM-105-01-F-DV-A**

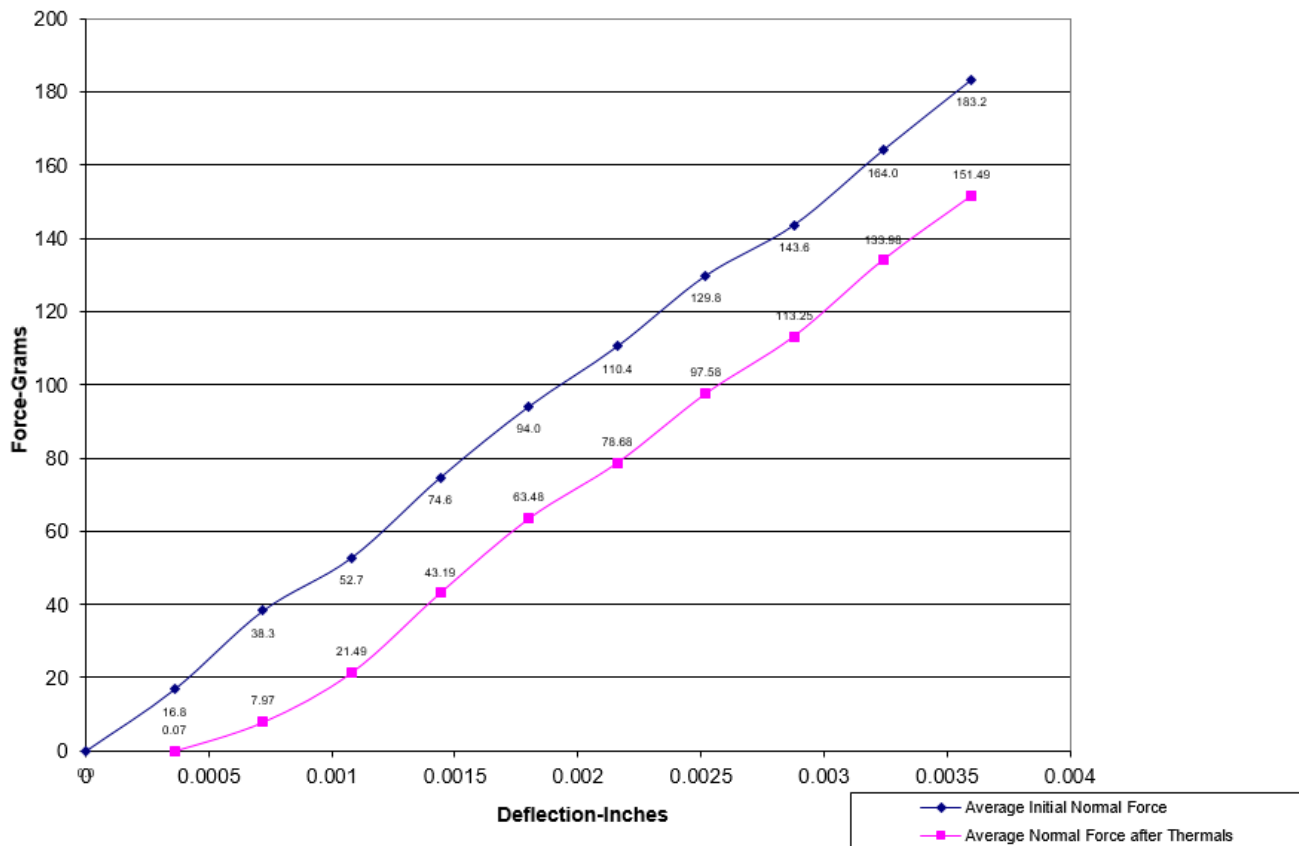
	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	8.36	1.88	5.92	1.33	9.34	2.10	8.05	1.81
Maximum	11.74	2.64	10.36	2.33	14.54	3.27	14.06	3.16
<b>Average</b>	10.12	<b>2.28</b>	8.03	<b>1.81</b>	11.92	<b>2.68</b>	10.48	<b>2.36</b>
St Dev	1.14	0.26	1.37	0.31	1.77	0.40	1.76	0.40
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	10.81	2.43	8.45	1.90	12.37	2.78	11.88	2.67
Maximum	16.24	3.65	15.66	3.52	18.19	4.09	16.99	3.82
<b>Average</b>	13.18	<b>2.96</b>	11.92	<b>2.68</b>	14.62	<b>3.29</b>	13.39	<b>3.01</b>
St Dev	1.73	0.39	2.00	0.45	1.68	0.38	1.56	0.35
Count	8	8	8	8	8	8	8	8
	After 100 Cycles							
	Mating		Unmating					
	Newtons	Force (Lbs)	Newtons	Force (Lbs)				
Minimum	13.74	3.09	13.12	2.95				
Maximum	18.73	4.21	17.53	3.94				
<b>Average</b>	15.70	<b>3.53</b>	14.24	<b>3.20</b>				
St Dev	1.55	0.35	1.44	0.32				
Count	8	8	8	8				

**DATA SUMMARIES Continued****NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):**

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

<b>Initial</b>	<b>Deflections in inches Forces in Grams</b>										
	<b>0.0004</b>	<b>0.0007</b>	<b>0.0011</b>	<b>0.0014</b>	<b>0.0018</b>	<b>0.0022</b>	<b>0.0025</b>	<b>0.0029</b>	<b>0.0032</b>	<b>0.0036</b>	<b>SET</b>
<b>Averages</b>	16.80	38.27	52.73	74.57	93.98	110.42	129.77	143.63	163.96	183.21	0.0002
<b>Min</b>	10.90	31.30	42.30	59.30	75.10	88.30	107.00	117.30	133.20	149.30	0.0000
<b>Max</b>	32.30	51.80	70.50	91.10	116.70	133.00	153.80	170.40	194.40	214.20	0.0003
<b>St. Dev</b>	5.467	6.944	9.282	10.190	12.792	13.977	16.202	17.956	20.505	21.830	0.0001
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12

<b>After Thermals</b>	<b>Deflections in inches Forces in Grams</b>										
	<b>0.0004</b>	<b>0.0007</b>	<b>0.0011</b>	<b>0.0014</b>	<b>0.0018</b>	<b>0.0022</b>	<b>0.0025</b>	<b>0.0029</b>	<b>0.0032</b>	<b>0.0036</b>	<b>SET</b>
<b>Averages</b>	0.07	7.97	21.49	43.19	63.48	78.68	97.58	113.25	133.98	151.49	0.0004
<b>Min</b>	-0.40	0.00	10.60	31.70	51.60	62.80	78.70	95.10	113.10	132.30	0.0001
<b>Max</b>	0.40	13.60	33.60	56.10	76.30	92.30	110.90	130.40	152.20	172.90	0.0007
<b>St. Dev</b>	0.337	4.994	8.019	8.221	8.608	9.251	9.960	9.921	13.007	14.399	0.0002
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12

**Normal Force - Average Initial vs Average Thermal**



**DATA SUMMARIES Continued****INSULATION RESISTANCE (IR):**

	Pin to Pin		
	Mated	Unmated	Unmated
Minimum	BCS/TSM	BCS	TSM
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

	Row to Row		
	Mated	Unmated	Unmated
Minimum	BCS/TSM	BCS	TSM
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

Voltage Rating Summary	
Minimum	BCS/TSM
Break Down Voltage	1997
Test Voltage	1500
Working Voltage	495

Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

**DATA SUMMARIES Continued****LLCR Thermal Aging Group**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:-----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:-----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:-----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms-----Unstable
  - f.  $>+1000$  mOhms:-----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	7/14/2020	7/28/2020		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	54	54		
Technician	Peter Chen	Peter Chen		
mOhm values	<b>Actual Initial</b>	<b>Delta Thermal</b>	<b>Delta</b>	<b>Delta</b>
<b>Pin Type 1: Signal</b>				
Average	4.48	0.05		
St. Dev.	0.25	0.04		
Min	3.96	0.00		
Max	5.43	0.36		
Summary Count	192	192		
Total Count	192	192		

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
mOhms	$\leq 5$	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	$>1000$
Thermal	192	0	0	0	0	0

**DATA SUMMARIES Continued****LLCR Mating/Unmating Durability Group**

- 1). A total of 192 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:-----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:-----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:-----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms:-----Unstable
  - f.  $> +1000$  mOhms:-----Open Failure

BCS-125-F-D-TE/TSM-125-01-F-DV-A

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	7/13/2020	7/14/2020	7/20/2020	7/31/2020
Room Temp (Deg C)	23	23	23	23
Rel Humidity (%)	54	57	54	54
Technician	Peter Chen	Peter Chen	Peter Chen	Peter Chen
mOhm values	<b>Actual</b>	<b>Delta</b>	<b>Delta</b>	<b>Delta</b>
	<b>Initial</b>	<b>100 Cycles</b>	<b>Therm Shck</b>	<b>Humidity</b>
<b>Pin Type 1: Signal</b>				
Average	4.42	0.13	0.15	0.16
St. Dev.	0.22	0.11	0.11	0.12
Min	3.85	0.00	0.00	0.00
Max	5.20	0.78	0.65	0.83
Summary Count	192	192	192	192
Total Count	192	192	192	192

<b>LLCR Delta Count by Category</b>						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	$\leq 5$	$>5$ & $\leq 10$	$>10$ & $\leq 15$	$>15$ & $\leq 50$	$>50$ & $\leq 1000$	$>1000$
100 Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	192	0	0	0	0	0

**DATA SUMMARIES Continued**

BCS-125-L-D-TE/TSM-125-01-L-DV-A

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	12/31/2021	1/7/2022	1/12/2022	1/24/2022
Room Temp (Deg C)	22	22	20	23
Rel Humidity (%)	50	52	50	51
Technician	Kason He	Kason He	Kason He	Keney Chen
mOhm values	<b>Actual</b>	<b>Delta</b>	<b>Delta</b>	<b>Delta</b>
	<b>Initial</b>	<b>100 Cycles</b>	<b>Therm Shck</b>	<b>Humidity</b>
<b>Pin Type 1: Signal</b>				
Average	4.44	0.14	0.20	0.21
St. Dev.	0.18	0.12	0.15	0.16
Min	3.99	0.00	0.00	0.01
Max	5.39	0.95	1.26	1.19
Summary Count	192	192	192	192
Total Count	192	192	192	192

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
mOhms	<b>&lt;=5</b>	<b>&gt;5 &amp; &lt;=10</b>	<b>&gt;10 &amp; &lt;=15</b>	<b>&gt;15 &amp; &lt;=50</b>	<b>&gt;50 &amp; &lt;=1000</b>	<b>&gt;1000</b>
<b>100 Cycles</b>	192	0	0	0	0	0
<b>Therm Shck</b>	192	0	0	0	0	0
<b>Humidity</b>	192	0	0	0	0	0

**DATA SUMMARIES Continued****LLCR Gas Tight Group**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:-----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: -----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:-----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:-----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms:-----Unstable
  - f.  $>+1000$  mOhms:-----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	7/13/2020	7/14/2020		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	54	54		
Technician	Peter Chen	Peter Chen		
mOhm values	<b>Actual Initial</b>	<b>Delta Acid Vapor</b>	<b>Delta</b>	<b>Delta</b>
<b>Pin Type 1: Signal</b>				
Average	4.68	0.48		
St. Dev.	0.42	0.42		
Min	3.83	0.00		
Max	5.77	1.68		
Summary Count	192	192		
Total Count	192	192		

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
mOhms	$\leq 5$	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	$>1000$
<b>Acid Vapor</b>	192	0	0	0	0	0

**DATA SUMMARIES Continued****LLCR Shock & Vibration Group**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:-----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:-----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:-----Marginal
  - e.  $+50.1$  to  $+1000$  mOhms-----Unstable
  - f.  $>+1000$  mOhms:-----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	8/18/2020	8/20/2020		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	50	47		
Technician	Scott Rollefstad	Scott Rollefstad		
<b>mOhm values</b>	<b>Actual</b>	<b>Delta</b>		
	<b>Initial</b>	<b>Shock-Vib</b>		
Pin Type: Signal 1				
Average	4.37	0.08		
St. Dev.	0.23	0.07		
Min	3.76	0		
Max	4.99	0.36		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	$\leq 5$	$>5$ & $\leq 10$	$>10$ & $\leq 15$	$>15$ & $\leq 50$	$>50$ & $\leq 1000$	$>1000$
Shock-Vib	192	0	0	0	0	0

**Nanosecond Event Detection:**

Shock and Vibration Event Detection Summary	
Contacts tested	192
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56g rms
Vibration Events	0
Total Events	0

**EQUIPMENT AND CALIBRATION SCHEDULES****Equipment #:** HZ-TCT-01**Description:** Normal force analyzer**Manufacturer:** Mecmesin Multitester**Model:** Mecmesin Multitester 2.5-i**Serial #:** 08-1049-04**Accuracy:** Last Cal: 4/26/2022, Next Cal: 4/25/2023**Equipment #:** HZ-OV-01**Description:** Oven**Manufacturer:** Huida**Model:** CS101-1E**Serial #:** CS101-1E-B**Accuracy:** Last Cal: 12/13/2021, Next Cal: 12/12/2022**Equipment #:** HZ-THC-01**Description:** Humidity transmitter**Manufacturer:** Thermtron**Model:** SM-8-8200**Serial #:** 38846**Accuracy:** Last Cal: 2/28/2022, Next Cal: 2/27/2023**Equipment #:** HZ-TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14994**Accuracy:** See Manual

... Last Cal: 06/28/2021, Next Cal: 06/27/2022

**Equipment #:** HZ-HPM-01**Description:** NA9636H**Manufacturer:** Ainuo**Model:** 6031A**Serial #:** 089601091**Accuracy:** Last Cal: 3/7/2022, Next Cal: 3/6/2023**Equipment #:** HZ-MO-05**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 1285188**Accuracy:** Last Cal: 11/15/2021, Next Cal: 11/14/2022

**EQUIPMENT AND CALIBRATION SCHEDULES Continued****Equipment #:** MO-04**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 0798688**Accuracy:** See Manual

... Last Cal: 04/30/2022, Next Cal: 04/30/2023

**Equipment #:** HZ-MO-01**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 2700**Serial #:** 1199807**Accuracy:** Last Cal: 04/28/2021, Next Cal: 04/28/2022**Equipment #:** HZ-PS-01**Description:** Power Supply**Manufacturer:** Agilent**Model:** 6031A**Serial #:** MY41000982**Accuracy:** Last Cal: 04/28/2021, Next Cal: 04/28/2022**Equipment #:** SVC-01**Description:** Shock & Vibration Table**Manufacturer:** Data Physics**Model:** LE-DSA-10-20K**Serial #:** 10037**Accuracy:** See Manual

... Last Cal: 11/31/2021, Next Cal: 11/31/2022

**Equipment #:** ACLM-01**Description:** Accelerometer**Manufacturer:** PCB Piezotronics**Model:** 352C03**Serial #:** 115819**Accuracy:** See Manual

... Last Cal: 07/09/2021, Next Cal: 07/09/2022

**Equipment #:** ED-03**Description:** Event Detector**Manufacturer:** Analysis Tech**Model:** 32EHD**Serial #:** 1100604**Accuracy:** See Manual

... Last Cal: 06/04/2021, Next Cal: 06/04/2022